



Recent Verigy Events

Summer has been a busy time for Verigy, hosting two major customer events in Asia, with venues in Taiwan, Korea and Singapore. In the Americas, Verigy was prominently positioned in SEMICON West, the largest semiconductor industry tradeshow event in the Americas.

1. Seminar and Forum in Asia

In June, Verigy presented its **SOC Technology Seminar** in Hsinchu, Taiwan and Seoul, Korea, attracting over 180 customers who appeared highly interested in the discussions of market trends and the Verigy product roadmap. Topics covered included “IC Testing Market Trends and Technical Challenges”, “Verigy Test Solutions”, “Consumer Mixed Signal”, “Blu-Ray DVD Application Test”, “Port Scale RF Adoption”, “PMIC Application Test”, and “Pin Scale 400 Adoption”.

Within the same week, Verigy also hosted an **executive RF Supply Chain Management Forum** in Singapore and Taiwan. The keynote was delivered by Michael Ellison, VP of Engineering, Qualcomm Inc.; he also participated in a follow-up panel discussion. All the major Asia Outsourced Semiconductor Assembly & Test (OSAT) companies were represented by their executives, who were delighted to meet with Mr. Ellison. In addition to Mr. Ellison, Qualcomm, and Frank Goh, Verigy Center of Expertise, panelists included (in Singapore) CK Tan, Executive Vice President, UTAC, and Kenneth Seah, Sr. Director, STATS ChipPAC; and (in Taiwan) Chender Huang, Director, TSMC, and Eric Yen, Director, ASET.



Panel discussion hosted by Verigy's John Cheng with participants: Michael Ellison (Qualcomm), Chender Huang (TSMC), Eric Yen (ASET). The executives honestly shared the challenges they have to address daily.

2. Tradeshow in U.S.



In July, Verigy participated in SEMICON West, in San Francisco, Calif., USA with a vital, active booth highlighting “The RIGHT Architecture” with solutions for SoC, RF, memory and yield improvement – all of which customers found very engaging. In addition, Verigy hosted a Financial Analyst meeting, and delivered three public presentations on Yield, RF and Memory Test. “Test Strategies - Improving Time To Yield”, presented at the TechXPOT by Debbara Ahlgren, VP and Chief Marketing Officer for Verigy, resulted in her photograph (article on p. 41) on the front page of the show’s Daily News!

